

FORM HDP-1449 (Based on Form PTO-1449) PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) Sheet 1 of 1	ATTORNEY DOCKET NO.	SERIAL NO.
	2500-000018	To be assigned
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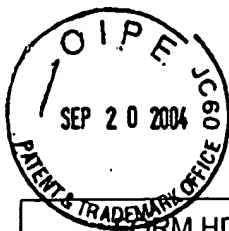
U.S. PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.	PTL	5,025,658	6/25/1991	Elings, et al.	 	
2.	PTL	5,144,833	9/8/1992	Amer, et al.	 	
3.	PTL	5,537,105	10/18/1994	Harp, et al.	 	
4.	PTL	5,567,872	10/22/1996	Kyogaku, et al.	 	

FOREIGN PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes No
1.						

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)		
Ref. Desig.	Examiner's Initials	
1.	PTL	S.A. MILLER, et al., Review of Scientific Instruments, 1997, vol 68, pp 4155
2.	PTL	C.A.J. PUTMAN, et al., Journal of Applied Physics, 1992, vol 72, issue 6
3.	PTL	T. SULCHEK, et al., Applied Physics Letters 2001, vol 78, pp 1786
4.	PTL	G. MEYER and N.M. AMER, Applied Physics Letters, 1990, vol 57, pp 2089

Examiner: <i>PTL</i>	Date Considered: 03.10.2006
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EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



FORM HDP-1449 (Based on Form PTO-1449)

**PATENT AND TRADEMARK OFFICE
INFORMATION DISCLOSURE CITATION**

(Use several sheets if necessary)

Sheet 1 of 1

ATTORNEY DOCKET No.

2500-000018

SERIAL No.

10/726,276

APPLICANT

Tuck Wah Ng

FILING DATE

12/2/2003

GROUP

2878

U.S. PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
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FOREIGN PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
1.							

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

Ref. Desig.	Examiner's Initials	
1.	<i>PK</i>	O. HANSEN and A. BOISEN, Noise in Piezoresistive atomic force microscopy, Nanotechnology 10 (1999), pp 51-60
2.	<i>PK</i>	A.E. SIEGMAN, An Introduction to Lasers and Masers, 1971, pp 304-321
3.	<i>PK</i>	O. SASAKI and H. OKAZAKI, Sinusoidal phase modulating interferometry for surface profile measurement, Applied Optics, 1986, Vol. 25, No. 18, pp 3137-3140
4.	<i>PK</i>	Powder Metallurgy Science, full density processing, pp 310-312

Examiner: *Patrick Connolly*Date Considered: *6.3.10.2004*

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